

**Electronic Design and Test Days 2021 - Conference Agenda High-Speed Digital Design**

CET	Topic	Tuesday, April 13, 2021 – Day 1 Presentations
09:00 – 09:10	Welcome	Introduction Martin Stumpf; Market Segment Manager, Rohde & Schwarz
09:10 - 09:45 incl. Q&A	A look into the SIPI toolbox - new tools and why they matter	<b>Signal and power integrity in high-speed digital design – challenges of increasing data rates</b> Jim Drewniak, President Clear Signal Solutions
09:45 – 10:20 incl. Q&A		<b>5 steps to a real-time eye diagram – signal integrity debugging</b> Guido Schulze, Product Manager Oscilloscopes, Rohde & Schwarz
10:20 – 10:55 incl. Q&A		<b>Beyond the horizon – Precise jitter and noise decomposition</b> Guido Schulze, Product Manager Oscilloscopes, Rohde & Schwarz
10:55 - 11:30	Break	Visit our educational and exhibition area.
11:30- 12:05 incl. Q&A	A look into the SIPI toolbox - new tools and why they matter	<b>Taking the test of high-speed PCBs and interconnects to the next level</b> Andrea D’Aquino, Product Manager Network Analyzer, Rohde & Schwarz
12:05- 12:40 incl. Q&A		<b>Improving power integrity and EMC in DC-DC converter designs</b> Robert Schillinger, Field Application Engineer at Würth Elektronik
12:40 – 14:15	<b>Break out - on demand: Educational Area</b> High-speed digital technology conference stream	<ul style="list-style-type: none"> <li>• Ethernet and automotive ethernet – beyond compliance</li> <li>• USB 3.2 interfaces – what to do if compliance fails</li> <li>• PCIe 3.0 – Compliance and debug solutions for systems &amp; cards</li> <li>• HDMI – Compliance and data eye analysis</li> <li>• DDR – Compliance and debug in one box</li> </ul>
14:15 – 14:50 incl. Q&A	High-speed digital – succeed in validation, debug and compliance	<b>USB-IF Compliance USB 2.0 &amp; 3.2 physical layer testing</b> Pascal Berten, Senior Certification Engineer at Eurofins Digital Testing Belgium
14:50 – 15:30	Break	Visit our educational and exhibition area.
15:30 – 16:05 incl. Q&A	High-speed digital – succeed in validation, debug and compliance	<b>Golden rules - Know your enemies when designing a PCIe Gen3 link</b> Hermann Ruckerbauer, EyeKnowHow
16:05		Wrap up / Closing

## Electronic Design and Test Days 2021 - Conference Agenda Power Electronics

CET	Topic	Title/ Wednesday, April 14, 2021 – Day 2 Presentations
09:00-09:10	Welcome	Introduction Dr. Markus Herdin, Market Segment Manager, Rohde & Schwarz
09:10 - 09:35	Component evaluation and testing	<b>Double-pulse testing – essentials</b> Dr. Markus Herdin, Market Segment Manager, Rohde & Schwarz
09:40 – 10:20 incl. Q&A		<b>The role of test &amp; measurement for design automation</b> Kevin Hermanns, Founder and Managing Director of PE-Systems
10:20 – 11:00	Break	Visit our educational and exhibition area.
11:00-11:35 incl. Q&A	Switching analysis and converter design	<b>From switching analysis towards robustness testing</b> Dr. Mathias Hellwig, Product Manager Oscilloscopes, Rohde & Schwarz
11:35-12:10 incl. Q&A		<b>Best practice on probing with high-voltage differential probes</b> Andreas Ibl, Product Manager Oscilloscopes, Rohde & Schwarz
12:10-12:45 incl. Q&A		<b>Specifics in control loop analysis for LED applications</b> Marcus Sonst, Application Development, Rohde & Schwarz
12:45 – 14:00	Break	Visit our educational and exhibition area.
14:00 – 14:35 Incl. Q&A	Keynote	<b>Silicon Carbide – The semiconductor material taking over high voltage power conversion</b> Dr. Chris Dries, CEO UnitedSiC
14:35 – 15:10 incl. Q&A	Battery and BMS simulation and testing	<b>Battery cell simulation for battery management system testing</b> Anja Fenske, Product Manager Power Supplies, Rohde & Schwarz
15:10 – 15:45 incl. Q&A		<b>Simulating high-voltage batteries in laboratory environments</b> Wolfgang Horrig, Sales Manager, Elektro-Automatik
15:45 - 16:15	Break	Visit our educational and exhibition area.
16:15 - 16:50 incl. Q&A	EMI debugging for power devices	<b>From Si to SiC - a rapid prototyping approach</b> Cam Pham, Global Automotive FAE leader, Cree – Wolfspeed Power
16:50 – 17:25 incl. Q&A		<b>Common-mode and differential mode noise – From optimizing EMI filter towards early testing and pre-compliance</b> Marcus Sonst, Application Development, Rohde & Schwarz
17:25		Wrap up / Closing